CIL EMU CRITICAL ITEMS LIST

5/30/2002 SUPERSEDES 12/31/2001

Page 1

Date: 4/24/2002

_ _ _ _ _

NAME P/N		FAILURE MODE &		
QTY	CRIT	CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
		350FM31		
DCM ELECTRONICS, ITEM 350 (PIVOTED, PLANAR) 	3/2RB	Loss of secondary SSER power. Electronic component failure, faulty solder joint, broken connection, output printed circuit trace shorts to ground.	END ITEM: Loss of secondary SSER power. GFE INTERFACE: Loss of secondary SSER power line. SSER will continue to operate from primary power line. MISSION: None for single failure. Terminate EVA for additional loss of primary SSER power line. CREW/VEHICLE: None. TIME TO EFFECT /ACTIONS: Seconds. TIME REQUIRED: Days. REDUNDANCY SCREENS: A-PASS B-FAIL C-PASS	 A. Design - Semiconductor failure is minimized through the use of high reliability components. Established reliability capacitors (Level S) and resistors (Level R) are used and are qualified to the requirements their respective MIL specs and thermal shocked per condition B of MIL-STD-202 Method 107. The transistors and diodes are qualified to the requirements of MIL-S-19500 and receive the burn-in of JANTXV level parts per the applicable methods, 1038, 1039, and 1040, of MIL-STD-750. The electronic components are operating within the power derating requirements of SVHS 7804 (derated to at least 75%). The printed circuit boards are polyinde per MIL-13949 Type GI and manufactured per SN-P-006. Parts mounting and soldering is per MSFC-STD-136 and NHB5300. 4 (3A-1). The board assemblies are hard mounted to the DCM case to provide a thermal transfer path between the board heat sinks and the case to direct heat away from the electronic components. The board assemblies are also conformal coated per MIL-A-46146 (Dow Corning RTV 3140) for environmental protections. All wiring used in the DCM is M22759/11 (teflon insulated). Soldering is per NNB5300. 4 (3A-1) and wire crimping is per SVHS 4909 (bases on MSC-SPEC-Q-1A). All wires are strain relieved. Electrical connectors are environmentally sealed to prevent damage due to contamination and humidity. B. Test - In-Process: The PCM electronics assembly is tested during initial build-up; at the board assembly level, after the PC boards have been interwired, after installation of the boards and wiring, and after installation of the front cover. These tests consist of continuity through the switches and wiring, voltage checks, functional check of all current limiters, and full operation of the DCM electronics. PDA: Vibration testing per SEMU-60-015 followed by continuity and full function, testing verifies the integrity of the solder joints and crimp connections in the DCM. The random vibration level for this test

CIL EMU CRITICAL ITEMS LIST			5/30/2002 SU	PERSEDES 12/31/2001	Page 2 Date: 4/24/2002
NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE	
		350FM31			
				and DCAS QA. All board assemblies are inspected for damage and contamination. All wiring is inspected for damage, nicks in the insulation, wear, and strain relief.	
				The DCM is internally inspected after installation of the circuit boards and wiring to insure no damage has occurred during assembly	
				D. Failure History - None.	
				E. Ground Turnaround - None for single failure.	
				F. Operational Use - Crew Response - Pre-EVA/EVA : No response, single failure undetectable by Special Training - No training specifically covers this failure mode. Operational Considerations - For single failure, no constraints Flight rules require tha if two-way communication between each EV crewmember and ork	crew or ground. at EVA be terminated biter, either direct

or through relay, is unavailable.

EXTRAVEHICULAR MOBILITY UNIT

SYSTEMS SAFETY REVIEW PANEL REVIEW

FOR THE

I-350 DCM ELECTRONIC ASSEMBLY

CRITICAL ITEM LIST (CIL)

EMU CONTRACT NO. NAS 9-97150

Prepared by:

S - Project Engineering

HS - Reliability

K. Munfard 4/24/02 HS - Engineering Manager

Approved by: 2

NASA Otew

An Program Manager